

TOSHIBA Bi-CMOS Integrated Circuit Silicon Monolithic

# TB62778FNG

## 8-Channel Constant-Current LED Driver of the 3.3-V and 5-V Power Supply Voltage Operation

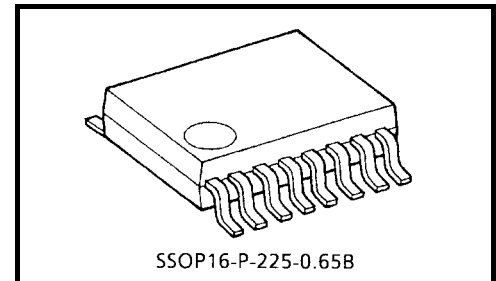
The TB62778FNG is comprised of constant-current drivers designed for LEDs and LED panel displays.

The regulated current sources are designed to provide a constant current, which is adjustable through one external resistor.

The TB62778FNG incorporates eight channels of shift registers, latches, AND gates and constant-current outputs.

Fabricated using the Bi-CMOS process, the TB62778FNG satisfies the system requirement of high-speed data transmission.

The TB62778FNG is RoHS.



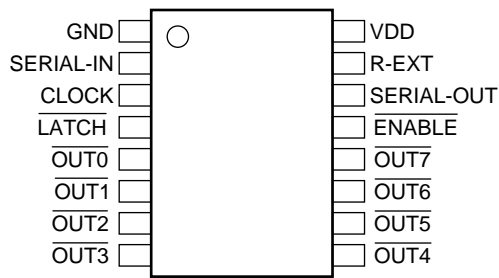
Weight: 0.07 g (typ.)

### Features

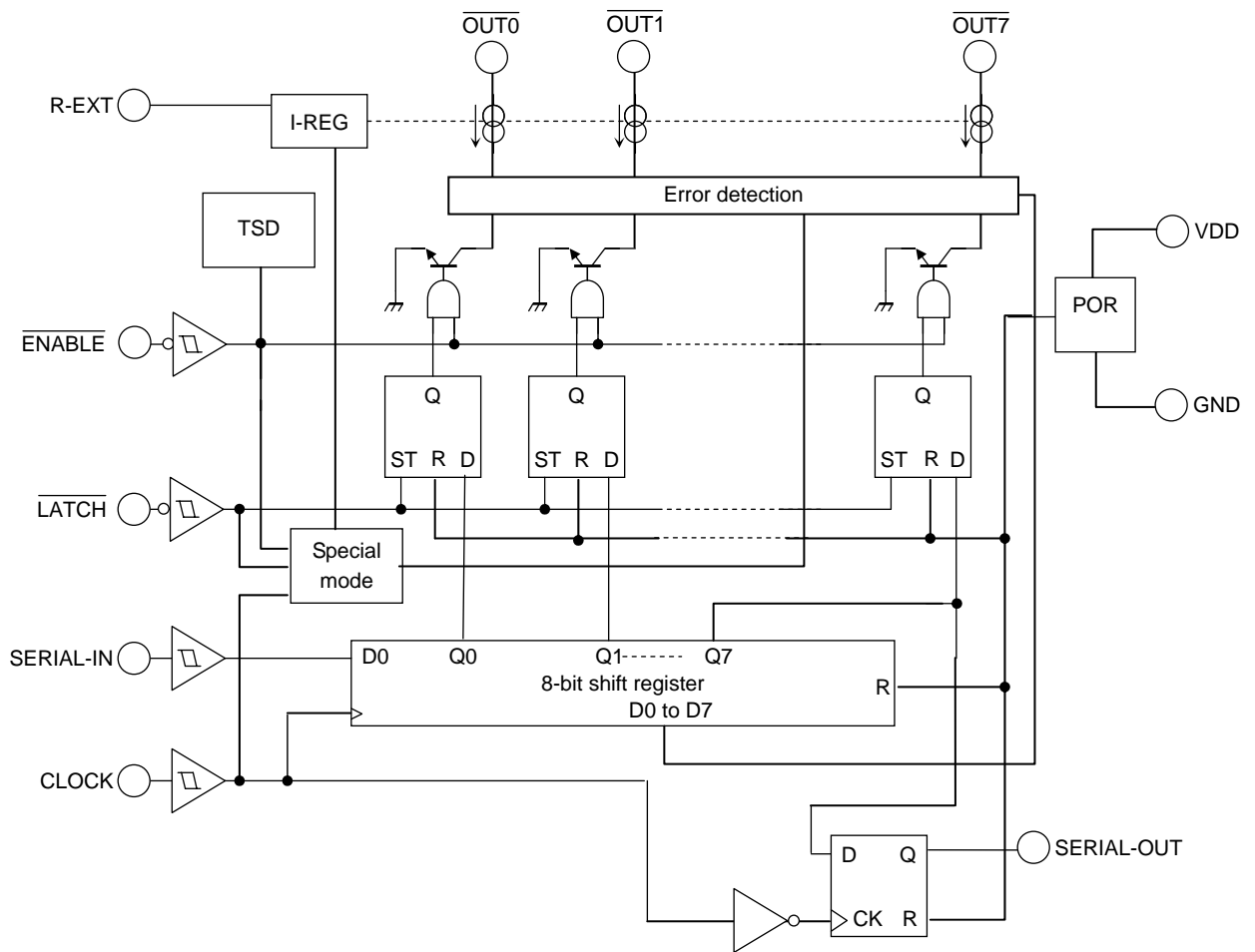
- Power supply voltages:  $V_{DD} = 3.3\text{ V}/5\text{ V}$
- Output drive capability and output count:  $50\text{ mA} \times 8\text{ channels}$
- Constant-current output range: 5 to 40 mA
- Voltage applied to constant-current output terminals: 0.4 V ( $I_{OUT} = 5\text{ to }40\text{ mA}$ )
- Current adjustment (via 7-bit serial data): The MSB, or the HC bit, selects the output current range: 25% to 50% range when HC = 0 or 50% to 100% range when HC = 1  
The six LSB bits are used to adjust the current in 64 steps within the selected range.
- Designed for common-anode LEDs
- Thermal shutdown (TSD)
- Power on reset (POR)
- Output-open detection (OOD) and output-short detection (OSD)
- Input signal voltage level: 3.3-V and 5-V CMOS interfaces (Schmitt trigger input)
- Maximum output voltage: 25V
- Serial data transfer rate: 25 MHz (max) @cascade connection
- Operating temperature range:  $T_{opr} = -40\text{ to }85^\circ\text{C}$
- Package: SSOP-P-225-0.65B
- Constant-current accuracy

Output Voltage	Current accuracy Between Channels	Current Accuracy Between ICs	Output Current
0.4 V to 4 V	±3%	±6%	15 mA

**Pin Assignment (top view)**



**Block Diagram**

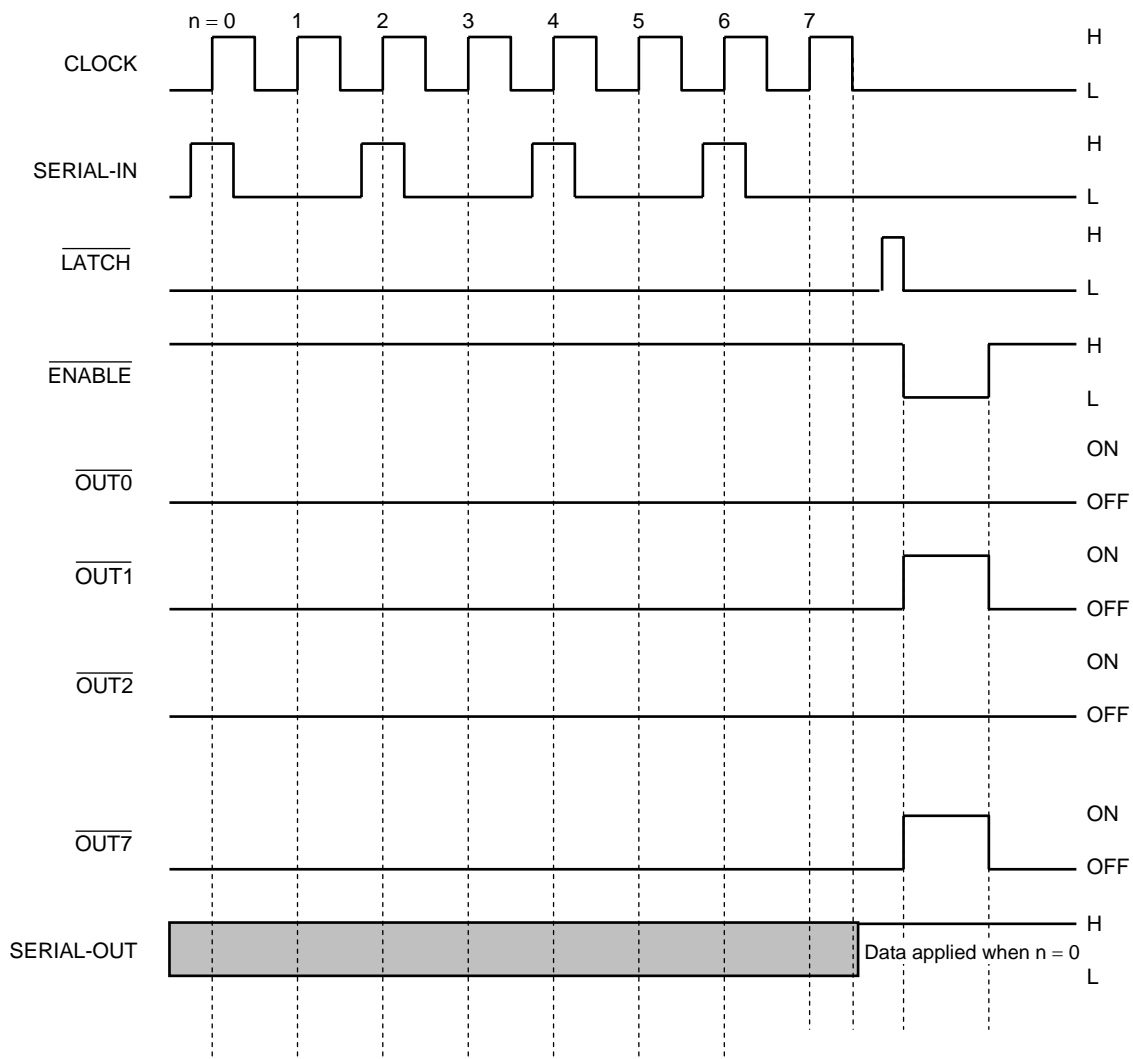


**Truth Table**

CLOCK	$\overline{\text{LATCH}}$	$\overline{\text{ENABLE}}$	SERIAL-IN	$\overline{\text{OUT0}}$ ... $\overline{\text{OUT5}}$ ... $\overline{\text{OUT7}}$	SERIAL-OUT
$\uparrow$	H	L	D <sub>n</sub>	D <sub>n</sub> ... D <sub>n-5</sub> ... D <sub>n-7</sub>	No change
$\uparrow$	L	L	D <sub>n+1</sub>	No Change	No change
$\uparrow$	H	L	D <sub>n+2</sub>	D <sub>n+2</sub> ... D <sub>n-3</sub> ... D <sub>n-5</sub>	No change
$\uparrow$	X	H	D <sub>n+3</sub>	OFF	No change
$\downarrow$	X	H	D <sub>n+3</sub>	OFF	D <sub>n-4</sub>

Note 1:  $\overline{\text{OUT0}}$  to  $\overline{\text{OUT7}}$  = On when D<sub>n</sub> = H;  $\overline{\text{OUT0}}$  to  $\overline{\text{OUT7}}$  = Off when D<sub>n</sub> = L.

**Timing Diagram**



Note 1: Latches are level-sensitive, not edge-triggered.

Note 2: The TB62778FNG can be used at 3.3 V or 5.0 V. However, the  $V_{DD}$  supply voltage must be equal to the input voltage.

Note 3: Serial data is shifted out of SERIAL-OUT on the falling edge of CLOCK.

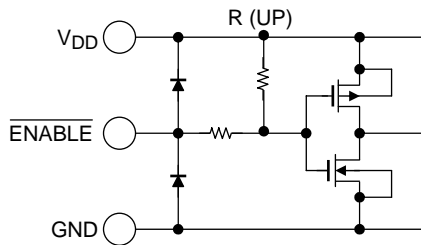
Note 4: The latches hold data while the  $\overline{\text{LATCH}}$  terminal is held Low. When the  $\overline{\text{LATCH}}$  terminal is High, the latches do not hold data and pass it transparently. When the  $\overline{\text{ENABLE}}$  terminal is Low,  $\overline{\text{OUT0}}$  to  $\overline{\text{OUT7}}$  toggle between ON and OFF according to the data. When the  $\overline{\text{ENABLE}}$  terminal is High,  $\overline{\text{OUT0}}$  to  $\overline{\text{OUT7}}$  are forced OFF.

**Terminal Description**

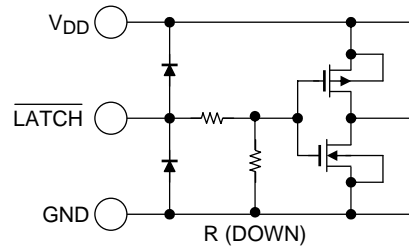
Pin No.	Pin Name	Function
1	GND	GND terminal
2	SERIAL-IN	Serial data input terminal
3	CLOCK	Serial clock input terminal
4	$\overline{\text{LATCH}}$	Latch input terminal
5	$\overline{\text{OUT0}}$	Constant-current output terminal
6	$\overline{\text{OUT1}}$	Constant-current output terminal
7	$\overline{\text{OUT2}}$	Constant-current output terminal
8	$\overline{\text{OUT3}}$	Constant-current output terminal
9	$\overline{\text{OUT4}}$	Constant-current output terminal
10	$\overline{\text{OUT5}}$	Constant-current output terminal
11	$\overline{\text{OUT6}}$	Constant-current output terminal
12	$\overline{\text{OUT7}}$	Constant-current output terminal
13	$\overline{\text{ENABLE}}$	Output enable input terminal All outputs ( $\overline{\text{OUT0}}$ to $\overline{\text{OUT7}}$ ) are disabled when the $\overline{\text{ENABLE}}$ terminal is driven High, and enabled when it is driven Low.
14	SERIAL-OUT	Serial data output terminal. Serial data is clocked out on the falling edge of CLOCK.
15	R-EXT	An external resistor is connected between this terminal and ground. $\overline{\text{OUT0}}$ to $\overline{\text{OUT7}}$ are adjusted to the same current value.
16	V <sub>DD</sub>	Power supply terminal

**Equivalent Circuits for Inputs and Outputs**

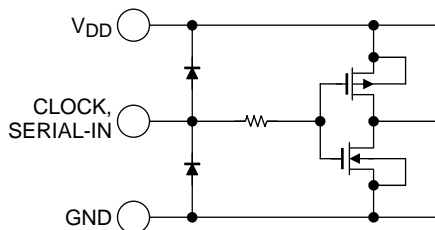
**1.  $\overline{\text{ENABLE}}$  Terminal**



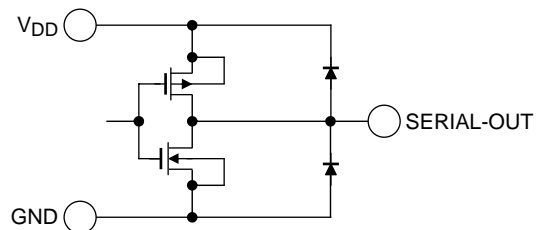
**2.  $\overline{\text{LATCH}}$  Terminal**



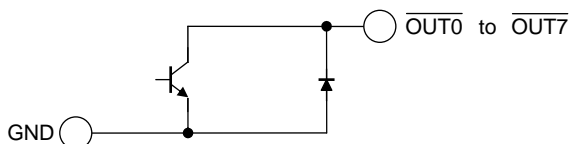
**3. CLOCK and SERIAL-IN Terminals**



**4. SERIAL-OUT Terminal**



**5.  $\overline{\text{OUT0}}$  to  $\overline{\text{OUT7}}$  Terminals**



## Absolute Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Supply voltage	V <sub>DD</sub>	6.0	V
Input voltage	V <sub>IN</sub>	-0.3 to V <sub>DD</sub> + 0.3 (Note 1)	V
Output current	I <sub>OUT</sub>	55	mA/ch
Output voltage	V <sub>OUT</sub>	0.3 to 25	V
Power dissipation	P <sub>d</sub>	1.02 (Notes 2 and 3)	W
Thermal resistance	R <sub>th(j-a)</sub>	122 (Note 2)	°C/W
Operating temperature range	T <sub>opr</sub>	-40 to 85	°C
Storage temperature range	T <sub>stg</sub>	-55 to 150	°C
Maximum junction temperature	T <sub>j</sub>	150	°C

Note 1: However, do not exceed 6.0 V.

Note 2: When mounted on a PCB (76.2 × 114.3 × 1.6 mm; Cu = 30%; 35-μm-thick; SEMI-compliant)

Note 3: Power dissipation is reduced by 1/R<sub>th(j-a)</sub> for each °C above 25°C ambient.

## Operating Ranges (unless otherwise specified, Ta = -40°C to 85°C)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Supply voltage	V <sub>DD</sub>	—	3	—	5.5	V
Output voltage	V <sub>OUT</sub>	$\overline{\text{OUT0}}$ to $\overline{\text{OUT7}}$	0.4	—	4	V
Output current	I <sub>OUT</sub>	$\overline{\text{OUT0}}$ to $\overline{\text{OUT7}}$	5	—	40	mA/ch
	I <sub>OH</sub>	SERIAL-OUT	—	—	-5	mA
	I <sub>OL</sub>	SERIAL-OUT	—	—	5	
Input voltage	V <sub>IH</sub>	SERIAL-IN/CLOCK/ LATCH / ENABLE	0.7 × V <sub>DD</sub>	—	V <sub>DD</sub>	V
	V <sub>IL</sub>		GND	—	0.3 × V <sub>DD</sub>	
Clock frequency	f <sub>CLK</sub>	Cascade connection	—	—	25	MHz
$\overline{\text{LATCH}}$ pulse width	t <sub>wLAT</sub>	(Note 2)	20	—	—	ns
CLOCK pulse width	t <sub>wCLK</sub>	(Note 2)	20	—	—	
$\overline{\text{ENABLE}}$ pulse width	t <sub>wENA</sub>	I <sub>OUT</sub> ≥ 20 mA (Note 2)	2	—	—	μs
		5 mA ≤ I <sub>OUT</sub> ≤ 20 mA (Note 2)	3	—	—	
Setup time	t <sub>SETUP1</sub>	(Note 2)	5	—	—	ns
	t <sub>SETUP2</sub>		5	—	—	
	t <sub>SETUP3</sub>		5	—	—	
	t <sub>SETUP4</sub>		5	—	—	
Hold time	t <sub>HOLD1</sub>		5	—	—	
	t <sub>HOLD2</sub>		5	—	—	
	t <sub>HOLD3</sub>		10	—	—	
	t <sub>HOLD4</sub>		10	—	—	
Maximum clock rise time	t <sub>r</sub>	Single operation (Notes 1 and 2)	—	—	5	μs
Maximum clock fall time	t <sub>f</sub>		—	—	5	

Note 1: For cascade operation, the CLOCK waveform might become ambiguous, causing the t<sub>r</sub> and t<sub>f</sub> values to be large. Then it may not be possible to meet the timing requirement for data transfer. Please consider the timing carefully.

Note 2: Please see the timing waveform on page 13.

Electrical Characteristics (Unless otherwise specified, Ta = 25°C, V<sub>DD</sub> = 4.5 to 5.5 V)

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Output current	I <sub>OUT1</sub>	5	V <sub>OUT</sub> = 0.4 V, R-EXT = 1.2 kΩ V <sub>DD</sub> = 5 V, V <sub>G</sub> = 1		15		mA
Output current error between ICs	ΔI <sub>OUT1</sub>	5	V <sub>OUT</sub> = 0.4 V, R-EXT = 1.2 kΩ All channels ON V <sub>DD</sub> = 5 V, V <sub>G</sub> = 1		±3	±6	%
Output current error between channels	ΔI <sub>OUT2</sub>	5	V <sub>OUT</sub> = 0.4 V, R-EXT = 1.2 kΩ All channels ON V <sub>DD</sub> = 5 V, V <sub>G</sub> = 1	—	±1	±3	%
Output leakage current	I <sub>OZ</sub>	5	V <sub>OUT</sub> = 25 V	—	—	1	μA
Input voltage	V <sub>IH</sub>	—	SERIAL-IN/CLOCK/LATCH / ENABLE	0.7 × V <sub>DD</sub>	—	V <sub>DD</sub>	V
	V <sub>IL</sub>	—	SERIAL-IN/CLOCK/LATCH / ENABLE	GND	—	0.3 × V <sub>DD</sub>	
Input current	I <sub>IH</sub>	2	V <sub>IN</sub> = V <sub>DD</sub> CLOCK/SERIAL-IN/ ENABLE			1	μA
	I <sub>IL</sub>	3	V <sub>IN</sub> = GND CLOCK/SERIAL-IN/ LATCH			-1	
SERIAL-OUT output voltage	V <sub>OL</sub>	1	I <sub>OL</sub> = 5.0 mA, V <sub>DD</sub> = 5 V	—	—	0.3	V
	V <sub>OH</sub>	1	I <sub>OH</sub> = -5.0 mA, V <sub>DD</sub> = 5 V	4.7	—	—	
OOD detection voltage	V <sub>OOD</sub>	7	5 to 40 mA	0.2	0.3	0.4	V
OSD detection voltage	V <sub>OSD</sub>	7	5 to 40 mA	0.9 × V <sub>DD</sub>	0.95 × V <sub>DD</sub>	V <sub>DD</sub>	V
Changes in constant output current dependent on V <sub>DD</sub>	%/V <sub>DD</sub>	5	V <sub>DD</sub> = 3 V to 5.5 V	—	1	2	%
Pull-up resistor	R (Up)	3	ENABLE	160	200	240	kΩ
Pull-down resistor	R (Down)	2	LATCH	160	200	240	kΩ
Supply current	I <sub>DD</sub> (OFF) 1	4	R-EXT = OPEN, V <sub>OUT</sub> = 25.0 V	—	—	1	mA
	I <sub>DD</sub> (OFF) 2	4	R-EXT = 1.2 kΩ, V <sub>OUT</sub> = 25.0 V, All channels OFF	—	—	5	
	I <sub>DD</sub> (ON)	4	R-EXT = 1.2 kΩ, V <sub>OUT</sub> = 0.4 V, All channels ON	—	—	9	

Switching Characteristics (Unless otherwise specified,  $T_a = 25^\circ\text{C}$ ,  $V_{DD} = 4.5$  to  $5.5\text{V}$ )

Characteristics	Symbol	Test Circuit	Test Condition (Note 1)	Min	Typ.	Max	Unit
Propagation delay time	$t_{pLH1}$	6	$\overline{\text{CLK}} - \overline{\text{OUTn}}$ , $\overline{\text{LATCH}} = \text{"H"}$ , $\overline{\text{ENABLE}} = \text{"L"}$	—	20	300	ns
	$t_{pLH2}$	6	$\overline{\text{LATCH}} - \overline{\text{OUTn}}$ , $\overline{\text{ENABLE}} = \text{"L"}$	—	20	300	
	$t_{pLH3}$	6	$\overline{\text{ENABLE}} - \overline{\text{OUTn}}$ , $\overline{\text{LATCH}} = \text{"H"}$	—	20	300	
	$t_{pLH}$	6	CLK-SERIAL OUT	2	10	14	
	$t_{pHL1}$	6	$\overline{\text{CLK}} - \overline{\text{OUTn}}$ , $\overline{\text{LATCH}} = \text{"H"}$ , $\overline{\text{ENABLE}} = \text{"L"}$	—	30	340	
	$t_{pHL2}$	6	$\overline{\text{LATCH}} - \overline{\text{OUTn}}$ , $\overline{\text{ENABLE}} = \text{"L"}$	—	70	340	
	$t_{pHL3}$	6	$\overline{\text{ENABLE}} - \overline{\text{OUTn}}$ , $\overline{\text{LATCH}} = \text{"H"}$	—	70	340	
	$t_{pHL}$	6	CLK-SERIAL OUT	2	10	14	
Output rise time	$t_{or}$	6	10% to 90% points of $\overline{\text{OUT0}}$ to $\overline{\text{OUT7}}$ voltage waveforms		20	150	
Output fall time	$t_{of}$	6	90% to 10% points of $\overline{\text{OUT0}}$ to $\overline{\text{OUT7}}$ voltage waveforms		125	300	

Note 1:  $T_{opr} = 25^\circ\text{C}$ ,  $V_{DD} = V_{IH} = 5\text{V}$ ,  $V_{IL} = 0\text{V}$ ,  $R_{EXT} = 1.2\text{k}\Omega$ ,  $I_{OUT} = 15\text{mA}$ ,  $V_L = 5.0\text{V}$ ,  
 $C_L = 10.5\text{pF}$  (see test circuit 6.)

Electrical Characteristics (Unless otherwise specified, Ta = 25°C, V<sub>DD</sub> = 3 to 3.6 V)

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Output current	I <sub>OUT1</sub>	5	V <sub>OUT</sub> = 0.4 V, R-EXT = 1.2 kΩ V <sub>DD</sub> = 3.3 V, V <sub>G</sub> = 1		15		mA
Output current error between ICs	ΔI <sub>OUT1</sub>	5	V <sub>OUT</sub> = 0.4 V, R-EXT = 1.2 kΩ All channels ON V <sub>DD</sub> = 3.3 V, V <sub>G</sub> = 1		±3	±6	%
Output current error between channels	ΔI <sub>OUT2</sub>	5	V <sub>OUT</sub> = 0.4 V, R-EXT = 1.2 kΩ All channels ON V <sub>DD</sub> = 3.3 V, V <sub>G</sub> = 1	—	±1	±3	%
Output leakage current	I <sub>OZ</sub>	5	V <sub>OUT</sub> = 25 V	—	—	1	μA
Input voltage	V <sub>IH</sub>	—	SERIAL-IN/CLOCK/LATCH / ENABLE	0.7 × V <sub>DD</sub>	—	V <sub>DD</sub>	V
	V <sub>IL</sub>	—	SERIAL-IN/CLOCK/LATCH / ENABLE	GND	—	0.3 × V <sub>DD</sub>	
Input current	I <sub>IH</sub>	2	V <sub>IN</sub> = V <sub>DD</sub> CLOCK/SERIAL-IN/LATCH / ENABLE			1	μA
	I <sub>IL</sub>	3	V <sub>IN</sub> = GND CLOCK/SERIAL-IN/LATCH / ENABLE			-1	
SERIAL-OUT output voltage	V <sub>OL</sub>	1	I <sub>OL</sub> = 5.0 mA, V <sub>DD</sub> = 3.3 V	—	—	0.3	V
	V <sub>OH</sub>	1	I <sub>OH</sub> = -5.0 mA, V <sub>DD</sub> = 3.3 V	3.0	—	—	
OOD detection voltage	V <sub>OOD</sub>	7	5 to 40 mA	0.2	0.3	0.4	V
OSD detection voltage	V <sub>OSD</sub>	7	5 to 40 mA	0.9 × V <sub>DD</sub>	0.95 × V <sub>DD</sub>	V <sub>DD</sub>	V
Changes in constant output current dependent on V <sub>DD</sub>	%/V <sub>DD</sub>	5	V <sub>DD</sub> = 3 V to 5.5 V	—	1	2	%
Pull-up resistor	R (Up)	3	ENABLE	160	200	240	kΩ
Pull-down resistor	R (Down)	2	LATCH	160	200	240	kΩ
Supply current	I <sub>DD</sub> (OFF) 1	4	R-EXT = OPEN, V <sub>OUT</sub> = 25.0 V	—	—	1	mA
	I <sub>DD</sub> (OFF) 2	4	R-EXT = 1.2 kΩ, V <sub>OUT</sub> = 25.0 V, All channels OFF	—	—	5	
	I <sub>DD</sub> (ON)	4	R-EXT = 1.2 kΩ, V <sub>OUT</sub> = 0.4 V, All channels ON	—	—	9	

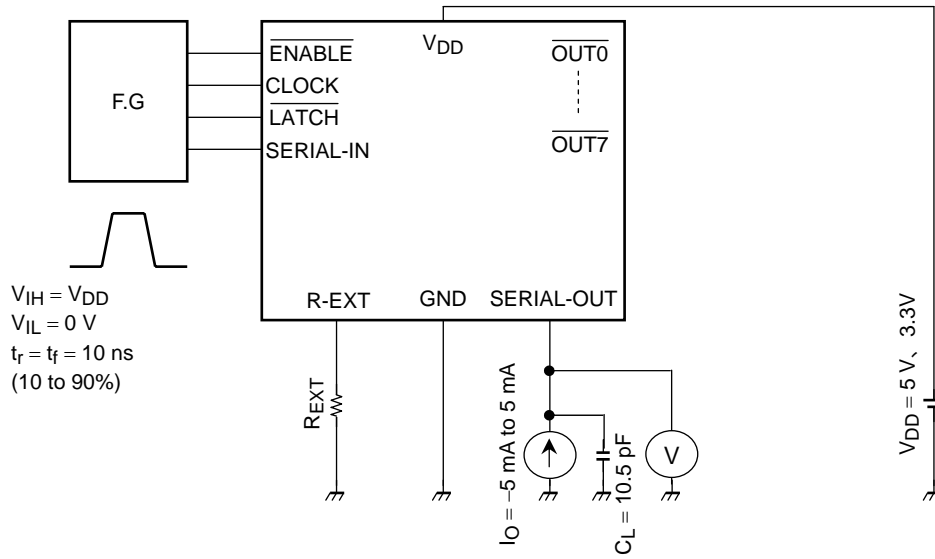
Switching Characteristics (Unless otherwise specified,  $T_a = 25^\circ\text{C}$ ,  $V_{DD} = 3$  to  $3.6$  V)

Characteristics	Symbol	Test Circuit	Test Condition (Note 1)	Min	Typ.	Max	Unit
Propagation delay time	$t_{pLH1}$	6	CLK- $\overline{\text{OUTn}}$ , $\overline{\text{LATCH}} = \text{"H"}$ , $\overline{\text{ENABLE}} = \text{"L"}$	—	—	300	ns
	$t_{pLH2}$	6	$\overline{\text{LATCH}} - \overline{\text{OUTn}}$ , $\overline{\text{ENABLE}} = \text{"L"}$	—	—	300	
	$t_{pLH3}$	6	$\overline{\text{ENABLE}} - \overline{\text{OUTn}}$ , $\overline{\text{LATCH}} = \text{"H"}$	—	—	300	
	$t_{pLH}$	6	CLK-SERIAL OUT	2	—	14	
	$t_{pHL1}$	6	CLK- $\overline{\text{OUTn}}$ , $\overline{\text{LATCH}} = \text{"H"}$ , $\overline{\text{ENABLE}} = \text{"L"}$	—	—	340	
	$t_{pHL2}$	6	$\overline{\text{LATCH}} - \overline{\text{OUTn}}$ , $\overline{\text{ENABLE}} = \text{"L"}$	—	—	340	
	$t_{pHL3}$	6	$\overline{\text{ENABLE}} - \overline{\text{OUTn}}$ , $\overline{\text{LATCH}} = \text{"H"}$	—	—	340	
	$t_{pHL}$	6	CLK-SERIAL OUT	2	—	14	
Output rise time	$t_{or}$	6	10% to 90% points of $\overline{\text{OUT0}}$ to $\overline{\text{OUT7}}$ voltage waveforms	—	—	150	
Output fall time	$t_{of}$	6	90% to 10% points of $\overline{\text{OUT0}}$ to $\overline{\text{OUT7}}$ voltage waveforms	—	—	300	

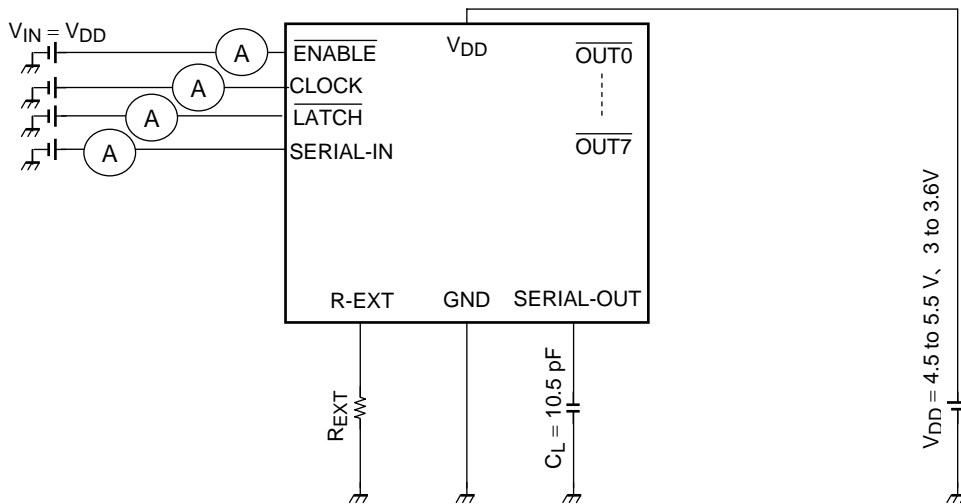
Note 1:  $T_{opr} = 25^\circ\text{C}$ ,  $V_{DD} = V_{IH} = 3.3$  V,  $V_{IL} = 0$  V,  $R_{EXT} = 1.2$  k $\Omega$ ,  $I_{OUT} = 15$  mA,  $V_L = 5.0$  V,  
 $C_L = 10.5$  pF (see test circuit 6.)

**Test Circuits**

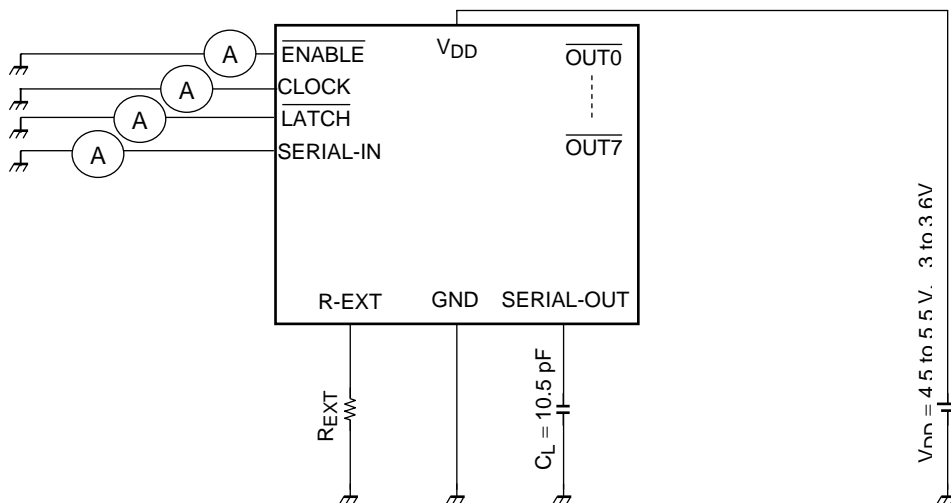
**Test Circuit 1: High-Level and Low-Level Input Voltages ( $V_{IH}/V_{IL}$ )**



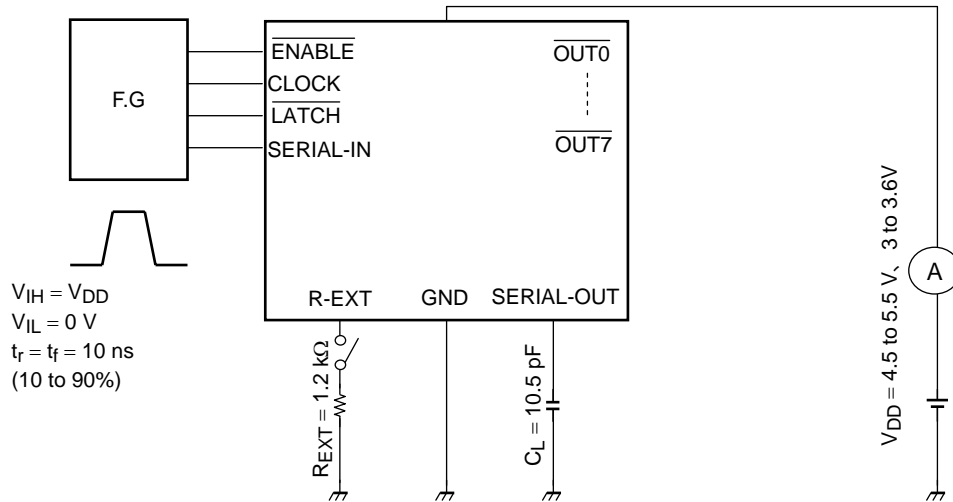
**Test Circuit 2: High-Level Input Current ( $I_{IH}$ )**



**Test Circuit 3: Low-Level Input Current ( $I_{IL}$ )**

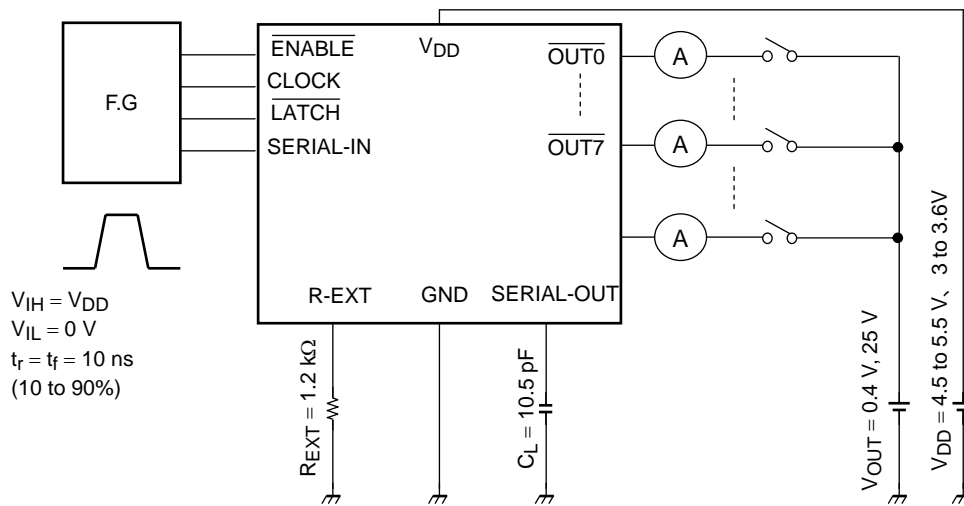


Test Circuit 4: Supply Current



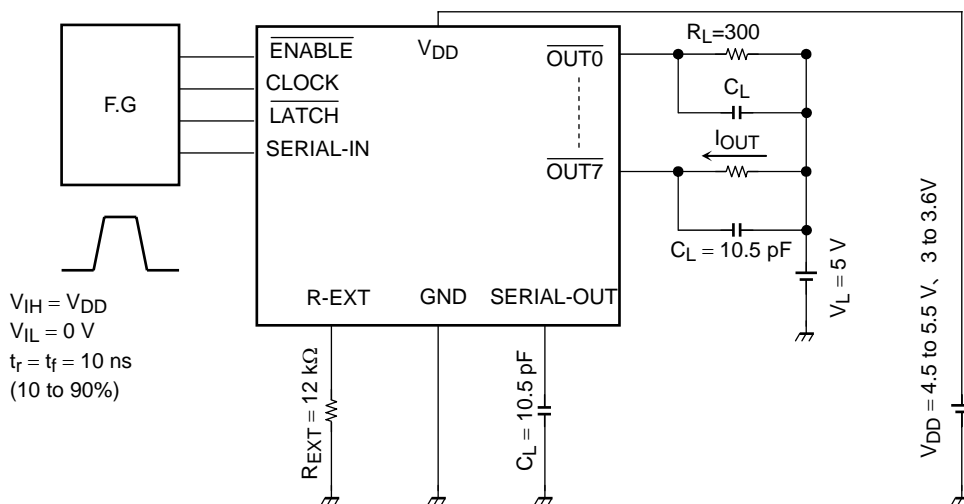
Note: The output terminal is based on the power supply current conditions on page 6 and 7.

Test Circuit 5: Output Current ( $I_{OUT1}$ ), Output Leakage Current ( $I_{OZ}$ ) Output Current Variations ( $\Delta I_{OUT1}/\Delta I_{OUT2}$ ), Current Variation with  $V_{DD}$  ( $\%/V_{DD}$ )

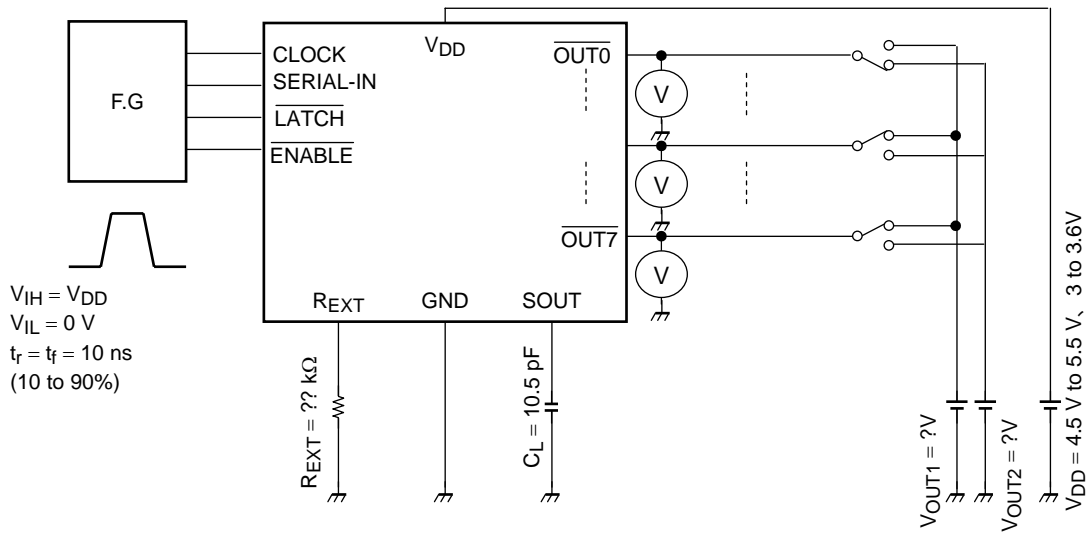


Theoretical output current =  $1.13 V/R_{EXT} \times 16$  (VG=1)

Test Circuit 6: Switching Characteristics

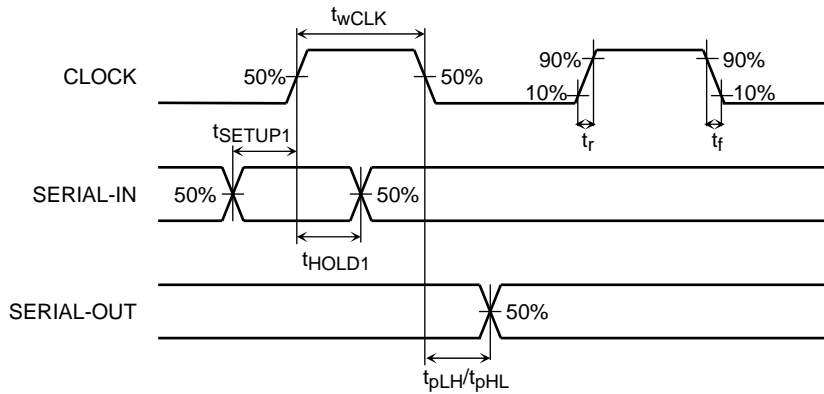


Test Circuit 7: ODD and OSD Characteristics

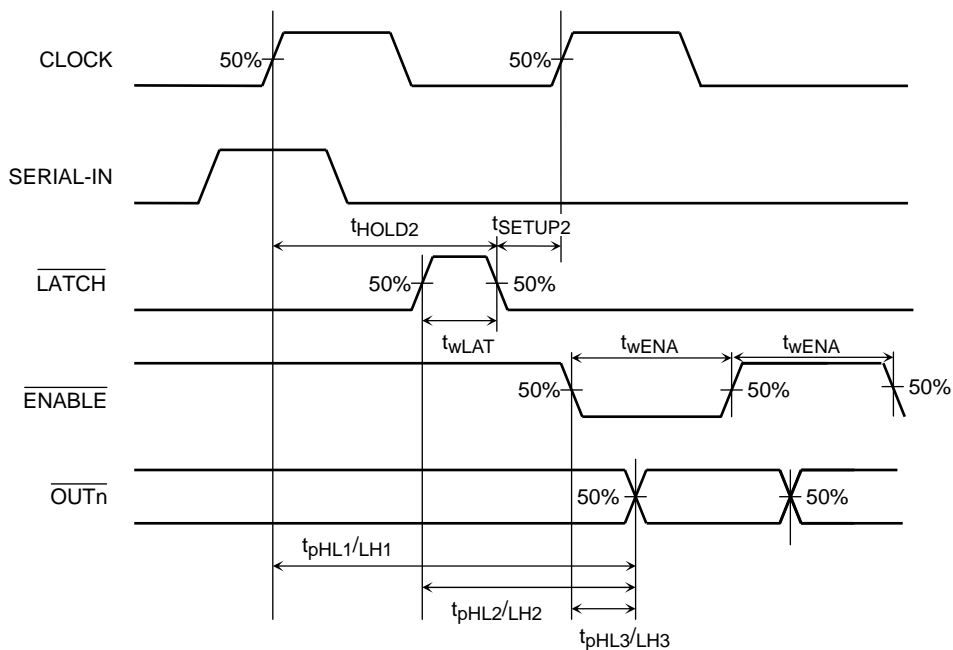


**Timing Waveforms**

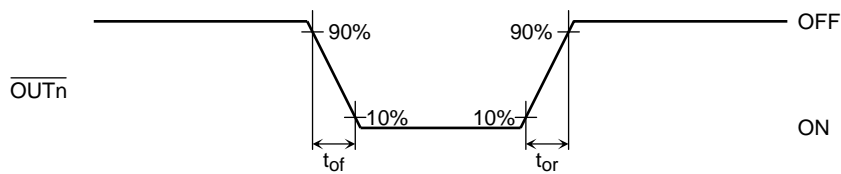
**1. CLOCK, SERIAL-IN, SERIAL-OUT**



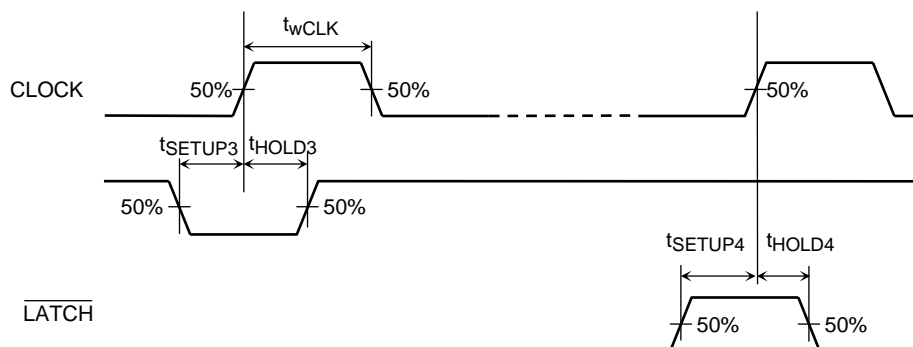
**2. CLOCK, SERIAL-IN, LATCH, ENABLE, OUTn**



**3. OUTn**



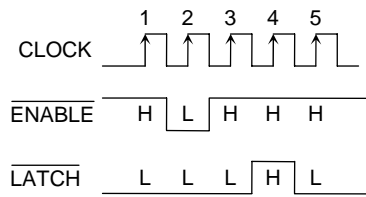
**4. Special Mode**



Note: The timing chart waveform may be simplified to explain a function and operation.  
Timing conditions must be taken care enough.

**Special Mode**

Sequence for Switching to Special Mode

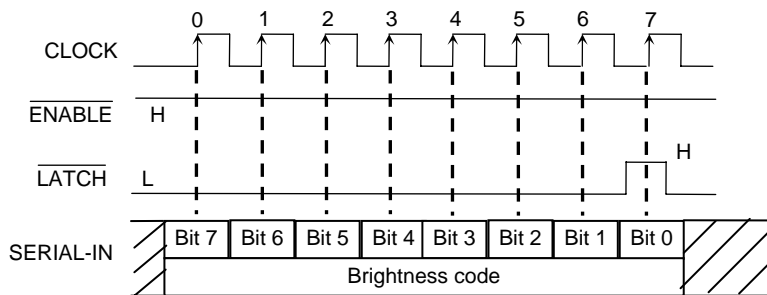


Only the above signal sequence puts the TB62778FNG in special mode. In this mode, two sub-modes are available: total brightness adjustment mode and error detection (OOD/OSD) mode.

While switching to special mode, data is not latched by  $\overline{\text{LATCH}}$ . After power-on, the TB62778FNG defaults to normal mode.

**Total Brightness Adjustment Mode**

Writing a brightness code



In total brightness adjustment mode, when  $\overline{\text{LATCH}}$  is High, a brightness code in the shift register is latched into the brightness adjustment register instead of the output latches. Once latched into the brightness adjustment register, the brightness code is held until the TB62778FNG is powered off or it is overwritten with a new code.

**Adjusting the total brightness**

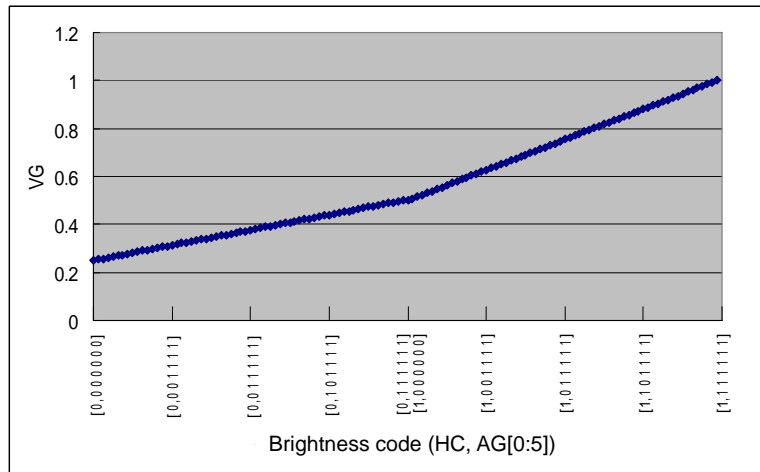
Bit definition of the brightness code

	Bit 0	Bit 1	Bit 2	Bit 3	Bit 4	Bit 5	Bit 6	Bit 7
	Reserved	HC	AG5	AG4	AG3	AG2	AG1	AG0
Default	1	1	1	1	1	1	1	1

The 8-bit brightness code is shifted in from the SERIAL-IN terminal, with bit 7 first. Bits 1 to 7 of the code determine the voltage applied to the R-EXT terminal (VG). Bit 1, HC, divides the voltage range into 25% to 50% (HC = 0) or 50% to 100% (HC = 1), and bits 2 to 7 are used to adjust the voltage in 64 steps within the range selected by bit 1. After on power, total brightness adjustment code becomes the above-mentioned default value.

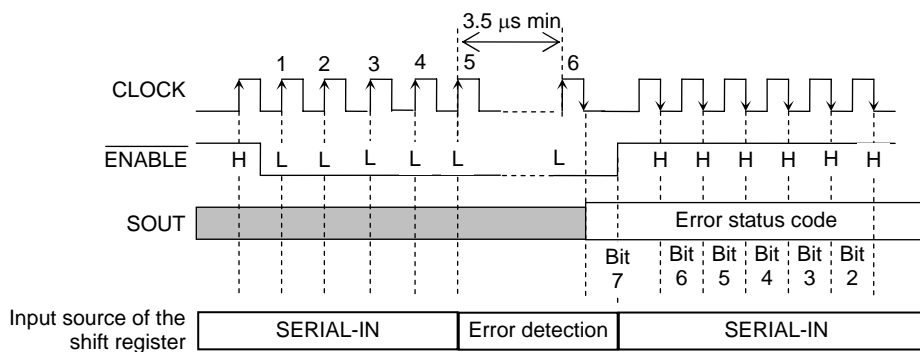
**Theoretical Current Settings (preliminary)**

$$\text{Current} = 1.13 \text{ V} \times \text{VG} \div \text{R-EXT} \times 16$$



Note) After setting up total luminance, it must be paid attention because the operation moves to the error detection mode (OOD) when five clocks are taken during the setting current output ( $\overline{\text{ENABLE}} = \text{L}$  period). (Please see the error detection mode on page 15.)

**Error Detection Mode 1 (OOD Detection)**

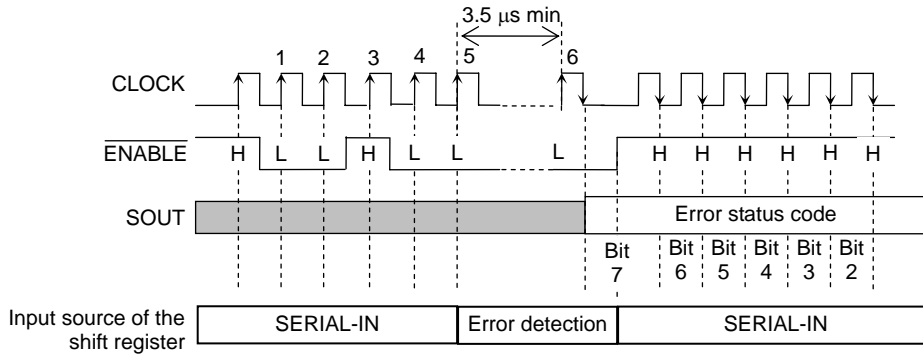


In special mode, the TB62778FNG not only enables the outputs but also performs error detection, and if any error is detected, loads an error status code into the shift register. For ODD detection, five Low bits must be shifted in. Immediately following the fifth Low bit, the input source of the shift register switches from the SERIAL-IN terminal to the 8-bit parallel error status code register. An error status code is generated at least 3.5μs from the fifth rising edge of CLOCK after  $\overline{\text{ENABLE}}$  is set Low. If any Low bit occurs thereafter, the detected error status code is saved in the shift register. Therefore, while  $\overline{\text{ENABLE}}$  is Low, serial data can not be shifted into the TB62778FNG via the SERIAL-IN terminal. Setting  $\overline{\text{ENABLE}}$  high changes the input source of the shift register to the SERIAL-IN terminal, disables the outputs and terminates error detection. Thereupon, new serial data is shifted into the TB62778FNG via the SERIAL-IN terminal while the error code in the shift register is shifted out from the SERIAL-OUT terminal on the falling edge of CLOCK. The output is Hi-Z when the output is turning off before OOD detection. So please execute the OOD detection after the output is turning on.

**Error Status Code in OOD Detection Mode**

	Error Status Code	Output Terminal State
$V_{\text{OOD}} \geq V_{\text{O}}$	0	Open
$V_{\text{OOD}} < V_{\text{O}}$	1	Normal

**Error Detection Mode 2 (OSD Detection)**



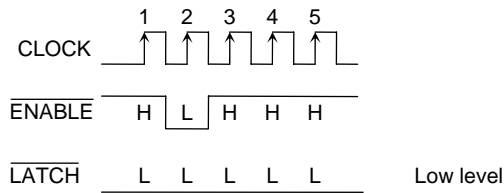
In special mode, the TB62778FNG not only enables the outputs but also performs error detection, and if any error is detected, loads an error status code into the shift register. For OSD detection, an L-L-H-L-L sequence must be shifted in. Immediately following the fifth Low bit, the input source of the shift register switches from the SERIAL-IN terminal to the 8-bit parallel error status code register. An error status code is generated at least 3.5  $\mu$ s from the fifth rising edge of CLOCK after  $\overline{\text{ENABLE}}$  is set Low. If any Low bit occurs thereafter, the detected error status code is saved in the shift register. Therefore, while  $\overline{\text{ENABLE}}$  is Low, serial data can not be shifted into the TB62778FNG via the SERIAL-IN terminal. Setting  $\overline{\text{ENABLE}}$  high changes the input source of the shift register to the SERIAL-IN terminal, disables the outputs and terminates error detection. Thereupon, new serial data is shifted into the TB62778FNG via the SERIAL-IN terminal while the error code in the shift register is shifted out from the SERIAL-OUT terminal on the falling edge of CLOCK. TB62778FNG is over the power dissipation when OSD detection. So please execute the OSD detection after the output is turning off.

**Error Status Code in OSD Detection Mode**

	Error Status Code	Output Terminal State
$V_{\text{OOD}} \leq V_{\text{O}}$	0	Shorted
$V_{\text{OOD}} > V_{\text{O}}$	1	Normal

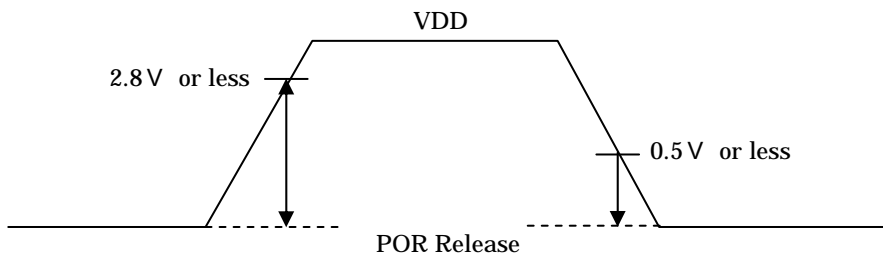
Note) The output current at the error detection mode is 25% of a set current (total brightness adjustment code (LSB) : minimum current setting).

**Sequence for Switching to Normal Mode**



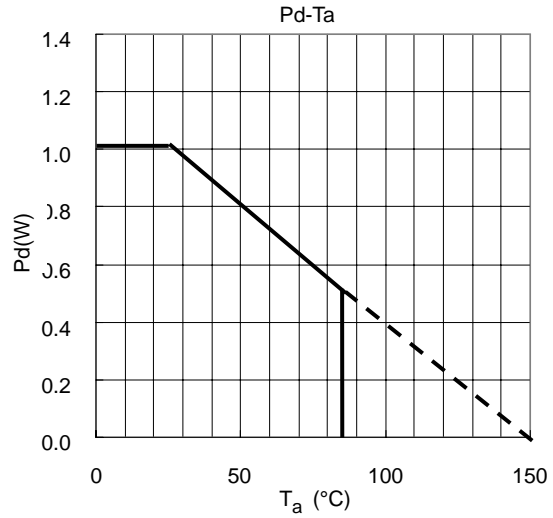
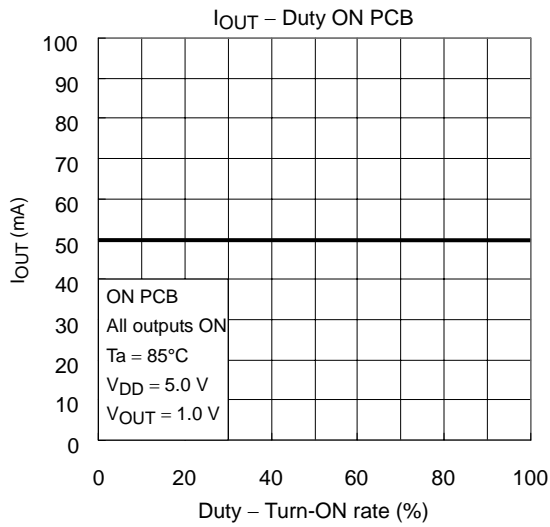
Only in the case of this signal sequence, it changes to the normal mode.  
Data is reset(0) when the mode is changes from the specified mode to the normal mode.

**POR Characteristic**

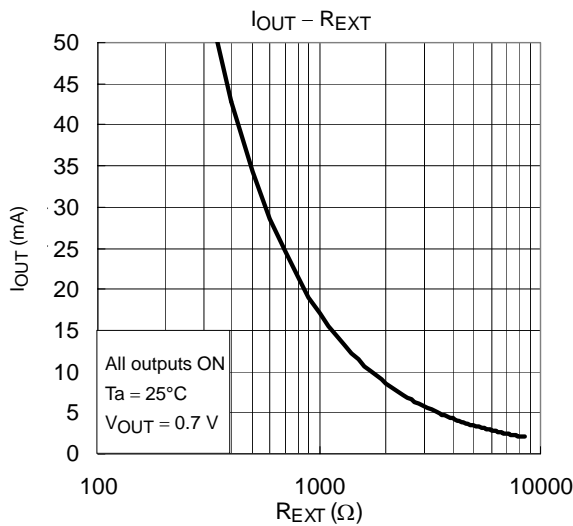


**Output current vs. Dirating (lighting rate) graph**

PCB Conditions: 76.2 × 114.3 × 1.6 mm, Cu = 30%, 35-μm Thick, SEMI-Compliant



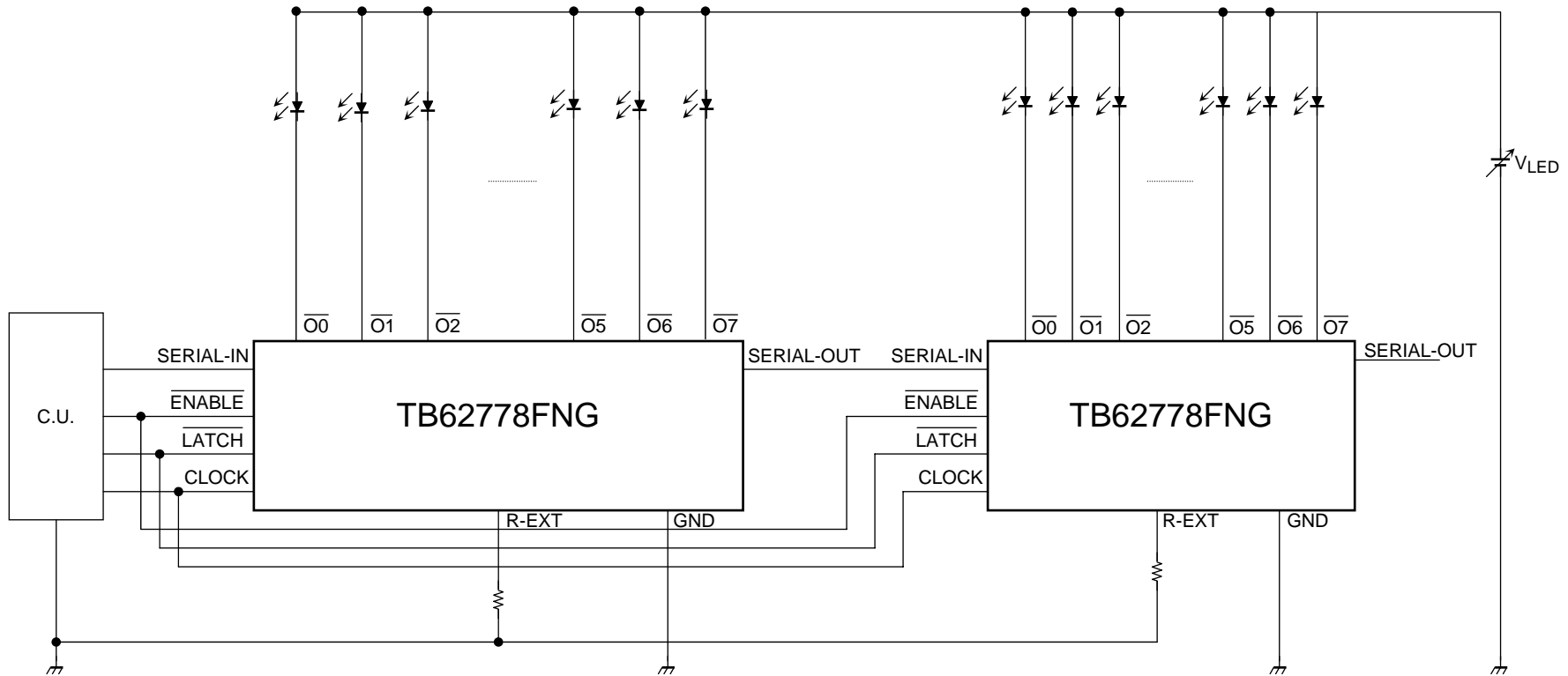
**Output Current vs. External Resistor (typ.)**



The above graphs are presented merely as a guide and does not constitute any guarantee as to the performance or characteristics of the device. Each product design should be fully evaluated in the real-world environment.

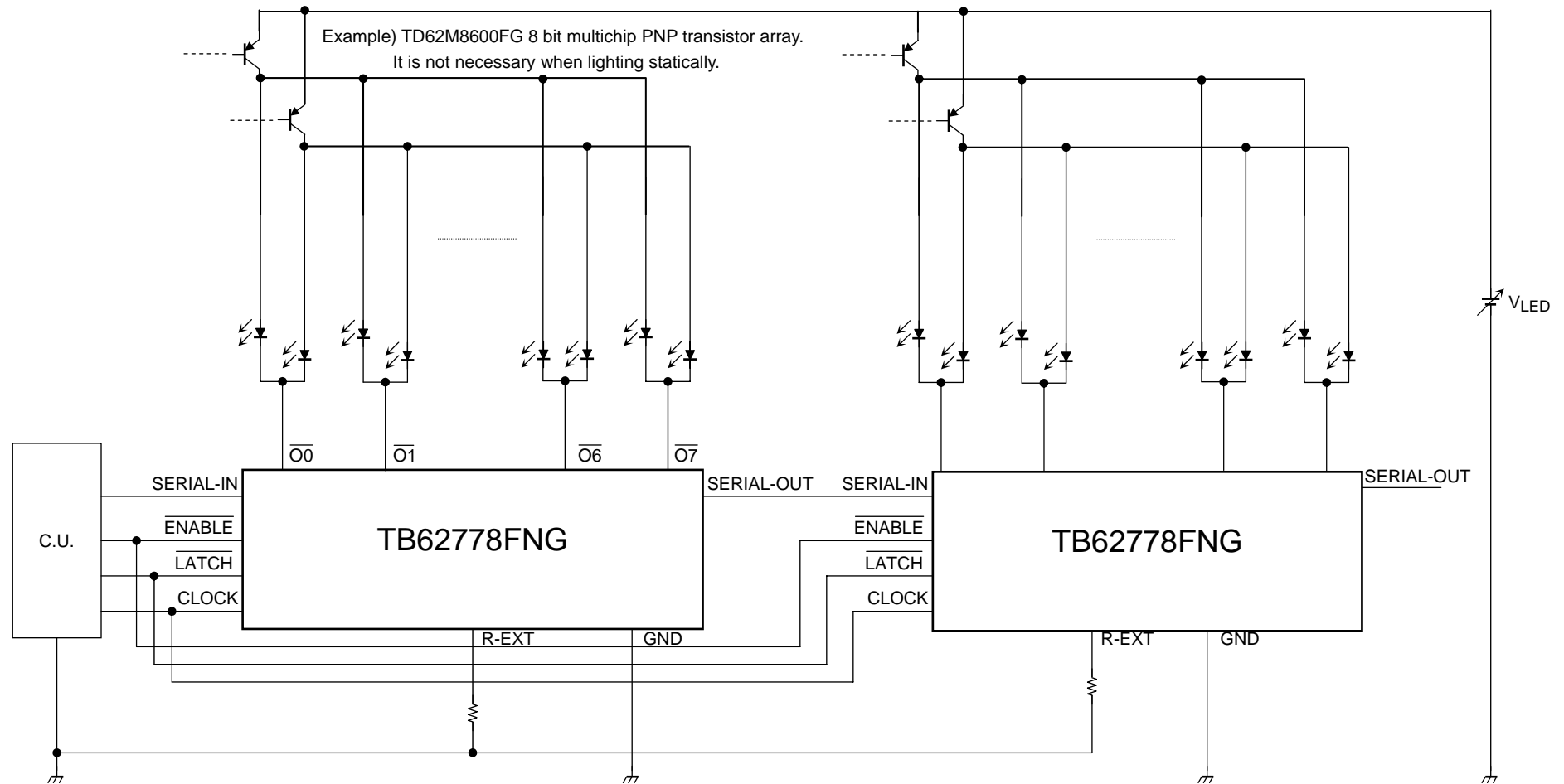
**Application Circuit: General Composition for Dynamic Lighting of LEDs**

In the following diagram, it is recommended that the LED supply voltage ( $V_{LED}$ ) be equal to or greater than the sum of  $V_f$  (max) of all LEDs plus 0.7 V.



**Application Circuit: General Composition for Dynamic Lighting of LEDs**

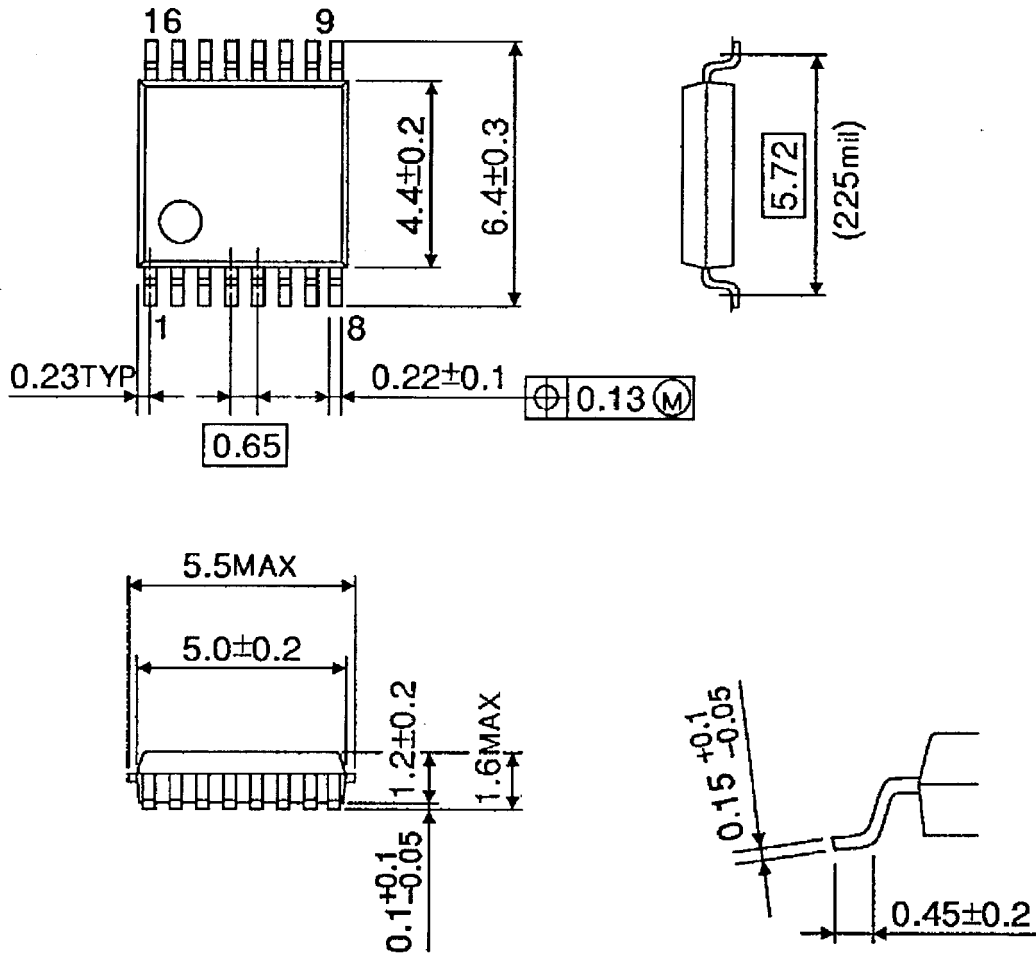
In the following diagram, it is recommended that the LED supply voltage ( $V_{LED}$ ) be equal to or greater than the sum of  $V_f$  (max) of all LEDs plus 0.7 V.



Package Dimensions

SSOP16-P-225-0.65B

Unit : mm



Weight: 0.07 g (typ.)

## Notes on Contents

### 1. Block Diagrams

Some of the functional blocks, circuits, or constants in the block diagram may be omitted or simplified for explanatory purposes.

### 2. Equivalent Circuits

The equivalent circuit diagrams may be simplified or some parts of them may be omitted for explanatory purposes.

### 3. Timing Charts

Timing charts may be simplified for explanatory purposes.

### 4. Application Circuits

The application circuits shown in this document are provided for reference purposes only. Thorough evaluation is required, especially at the mass production design stage.

Toshiba does not grant any license to any industrial property rights by providing these examples of application circuits.

### 5. Test Circuits

Components in the test circuits are used only to obtain and confirm the device characteristics. These components and circuits are not guaranteed to prevent malfunction or failure from occurring in the application equipment.

## IC Usage Considerations

### Notes on handling of ICs

- (1) The absolute maximum ratings of a semiconductor device are a set of ratings that must not be exceeded, even for a moment. Do not exceed any of these ratings.  
Exceeding the rating(s) may cause the device breakdown, damage or deterioration, and may result injury by explosion or combustion.
- (2) Use an appropriate power supply fuse to ensure that a large current does not continuously flow in case of over current and/or IC failure. The IC will fully break down when used under conditions that exceed its absolute maximum ratings, when the wiring is routed improperly or when an abnormal pulse noise occurs from the wiring or load, causing a large current to continuously flow and the breakdown can lead smoke or ignition. To minimize the effects of the flow of a large current in case of breakdown, appropriate settings, such as fuse capacity, fusing time and insertion circuit location, are required.
- (3) If your design includes an inductive load such as a motor coil, incorporate a protection circuit into the design to prevent device malfunction or breakdown caused by the current resulting from the inrush current at power ON or the negative current resulting from the back electromotive force at power OFF. IC breakdown may cause injury, smoke or ignition.  
Use a stable power supply with ICs with built-in protection functions. If the power supply is unstable, the protection function may not operate, causing IC breakdown. IC breakdown may cause injury, smoke or ignition.
- (4) Do not insert devices in the wrong orientation or incorrectly.  
Make sure that the positive and negative terminals of power supplies are connected properly. Otherwise, the current or power consumption may exceed the absolute maximum rating, and exceeding the rating(s) may cause the device breakdown, damage or deterioration, and may result injury by explosion or combustion.  
In addition, do not use any device that is applied the current with inserting in the wrong orientation or incorrectly even just one time.

- (5) Carefully select external components (such as inputs and negative feedback capacitors) and load components (such as speakers), for example, power amp and regulator.  
If there is a large amount of leakage current such as input or negative feedback condenser, the IC output DC voltage will increase. If this output voltage is connected to a speaker with low input withstand voltage, overcurrent or IC failure can cause smoke or ignition. (The over current can cause smoke or ignition from the IC itself.) In particular, please pay attention when using a Bridge Tied Load (BTL) connection type IC that inputs output DC voltage to a speaker directly.

**Points to remember on handling of ICs**

- (1) Over current Protection Circuit  
Over current protection circuits (referred to as current limiter circuits) do not necessarily protect ICs under all circumstances. If the Over current protection circuits operate against the over current, clear the over current status immediately.  
Depending on the method of use and usage conditions, such as exceeding absolute maximum ratings can cause the over current protection circuit to not operate properly or IC breakdown before operation. In addition, depending on the method of use and usage conditions, if over current continues to flow for a long time after operation, the IC may generate heat resulting in breakdown.
- (2) Back-EMF  
When a motor rotates in the reverse direction, stops or slows down abruptly, a current flow back to the motor's power supply due to the effect of back-EMF. If the current sink capability of the power supply is small, the device's motor power supply and output pins might be exposed to conditions beyond maximum ratings. To avoid this problem, take the effect of back-EMF into consideration in system design.

About solderability, following conditions were confirmed

- Solderability
  - (1) Use of Sn-37Pb solder Bath
    - solder bath temperature = 230°C
    - dipping time = 5 seconds
    - the number of times = once
    - use of R-type flux
  - (2) Use of Sn-3.0Ag-0.5Cu solder Bath
    - solder bath temperature = 245°C
    - dipping time = 5 seconds
    - the number of times = once
    - use of R-type flux

## RESTRICTIONS ON PRODUCT USE

070122EBA

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